

The eGaN[®] FET
Journey Continues

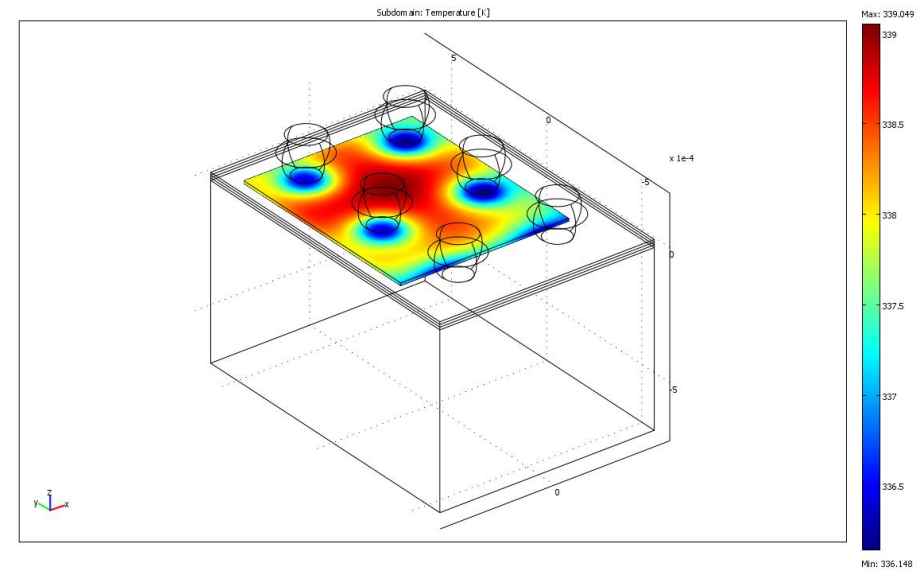
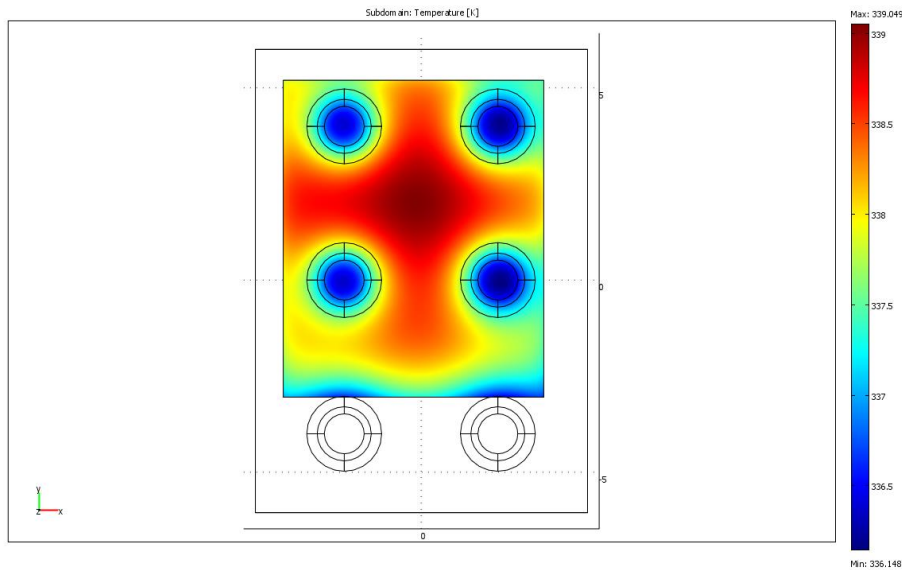


EPC2216 Thermal Model

Efficient Power Conversion Corporation

Steady State $R_{\Theta JB}$

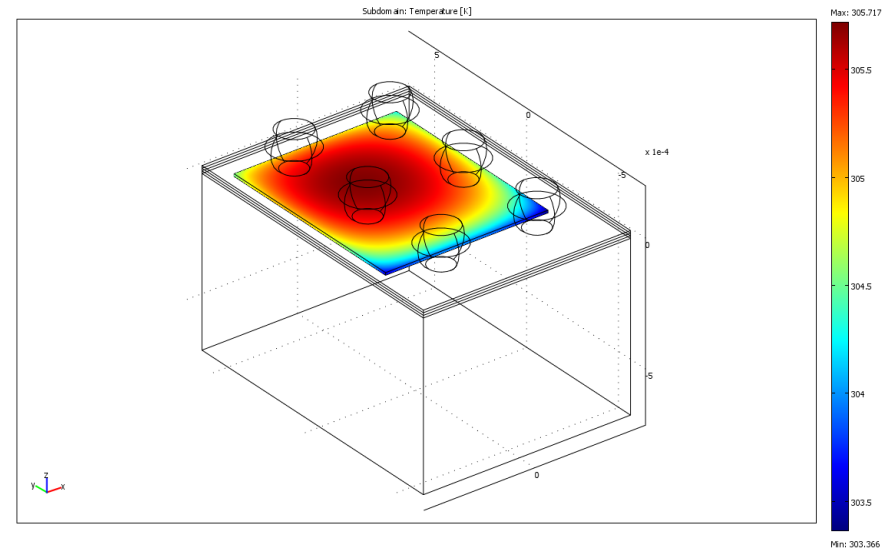
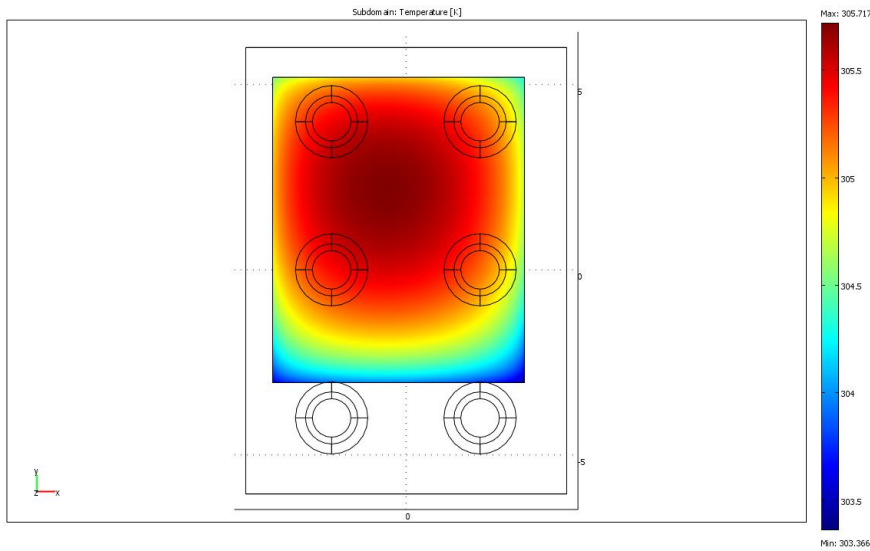
- $R_{\Theta JB} = 39 \text{ }^{\circ}\text{C/W}$



- 1 W dissipation in active volume
- Top of bumps at 300K

Steady State $R_{\Theta JC}$

- $R_{\Theta JC} = 5.7 \text{ } ^\circ\text{C/W}$

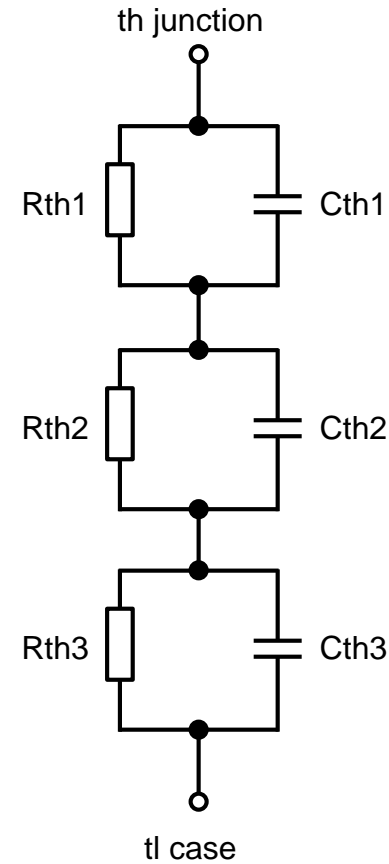


- 1 W dissipation in active volume
- Backside Si at 300K

Transient $Z_{\Theta JB}$

- 1 W total is dissipated in the device

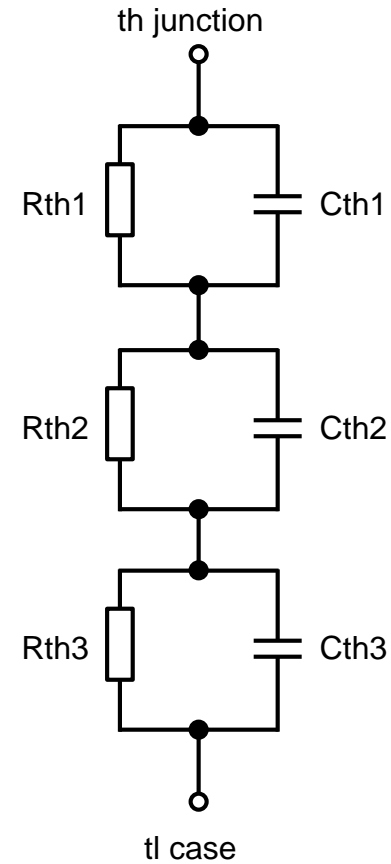
Fitting parameter	Value	Unit
Rth1	36.7	°C/W
Rth2	1.9	
Rth3	3.78E-1	
Cth1	1.52E-3	J/°C
Cth2	3.54E-4	
Cth3	2.62E-4	



Transient $Z_{\Theta JC}$

- 1 W total is dissipated in the device

Fitting parameter	Value	Unit
Rth1	3.99	°C/W
Rth2	1.6	
Rth3	1.08E-1	
Cth1	9.68E-4	J/°C
Cth2	1.98E-4	
Cth3	9.61E-4	





*The end of the
road for silicon...*

*but a clear road
ahead for GaN
FETs and ICs!*